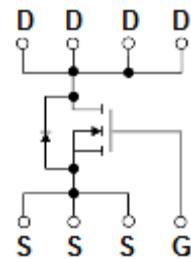


## Features

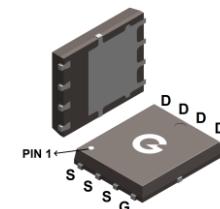
- Advanced shielded-gate technology
- Ultra-low on-resistance and gate-charge
- JESD22-A114-B ESD rating of class 1B per human body model

**HF**



## Applications

- High-frequency DC-to-DC convertors
- Motor controllers
- Battery management and protection
- Server power



**PDFN5x6-8L**

## Mechanical Data

- Case: PDFN5x6-8L
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208

## Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
BL030N03T-5DL8	PDFN5x6-8L	5000 pcs / Tape & Reel	030N03T

## Maximum Ratings (@ $T_c = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	$V_{DSS}$	30	V
Gate-to-Source Voltage	$V_{GSS}$	$\pm 20$	V
Continuous Drain Current ( $T_c = 25^\circ\text{C}$ )	$I_D$	135	A
Continuous Drain Current ( $T_c = 100^\circ\text{C}$ )		85	A
Pulsed Drain Current ( $t_p = 10\mu\text{s}$ , $T_c = 25^\circ\text{C}$ )	$I_{DM}$	600	A
Single Pulse Avalanche Energy <sup>*2</sup>	$E_{AS}$	28	mJ

## Thermal Characteristics

Parameter	Symbol	Value	Unit
Power Dissipation ( $T_c = 25^\circ\text{C}$ )	$P_D$	83	W
Thermal Resistance Junction-to-Air <sup>*1</sup>	$R_{\theta JA}$	30	°C/W
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	1.5	°C/W
Operating Junction Temperature Range	$T_J$	-55 ~ +150	°C
Storage Temperature Range	$T_{STG}$	-55 ~ +150	°C

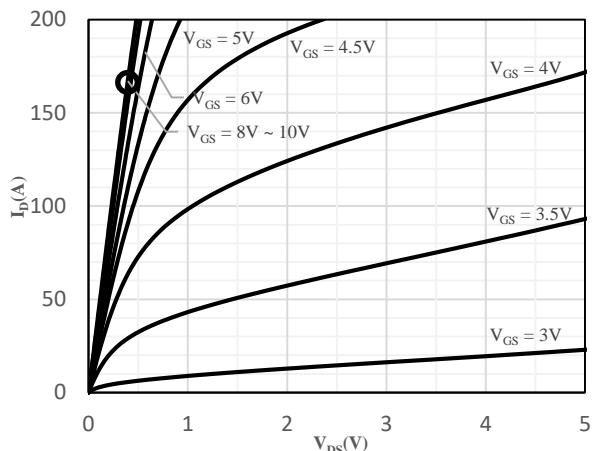
**Electrical Characteristics** (@  $T_J = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu\text{A}$	30	-	-	V
$I_{DS(0)}$	Zero Gate Voltage Drain Current	$V_{DS} = 30V, V_{GS} = 0V$	-	-	1	$\mu\text{A}$
$I_{GSS}$	Gate-Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	$\pm 100$	nA
<b>On Characteristics</b> <sup>*3</sup>						
$R_{DS(ON)}$	Static Drain-Source On-resistance	$V_{GS} = 10V, I_D = 20A$	-	2.5	3.1	$\text{m}\Omega$
		$V_{GS} = 5V, I_D = 20A$	-	3.4	4.6	$\text{m}\Omega$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.6	2.5	V
$R_G$	Gate Resistance	$V_{GS} = 0V, f = 1\text{MHz}$	-	3.5	-	$\Omega$
<b>Dynamic Characteristics</b>						
$C_{ISS}$	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 15V$ $f = 1.0\text{MHz}$	-	2472	-	pF
$C_{OSS}$	Output Capacitance		-	1186	-	
$C_{RSS}$	Reverse Transfer Capacitance		-	64	-	
<b>Switching Characteristics</b>						
$t_{d(\text{ON})}$	Turn-on Delay Time	$V_{DD} = 15V, V_{GS} = 10V$ $R_G = 3.0\Omega, I_D = 20A$	-	14	-	ns
$t_r$	Turn-on Rise Time		-	6	-	
$t_{d(\text{OFF})}$	Turn-Off Delay Time		-	28	-	
$t_f$	Turn-Off Fall Time		-	14	-	
$Q_G$	Total Gate-Charge	$V_{DD} = 15V$ $V_{GS} = 10V$ $I_D = 20A$	-	36.5	-	nC
$Q_{GS}$	Gate to Source Charge		-	8	-	
$Q_{GD}$	Gate to Drain (Miller) Charge		-	5.5	-	
<b>Source-Drain Diode Characteristics</b>						
$V_{SD}$	Diode Forward Voltage	$I_{SD} = 20A, V_{GS} = 0V$	-	0.8	1.2	V
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F = 20A, V_{GS} = 0V$ $di/dt = 100A/\mu\text{s}$	-	95	-	ns
$Q_{rr}$	Body Diode Reverse Recovery charge		-	105	-	nC

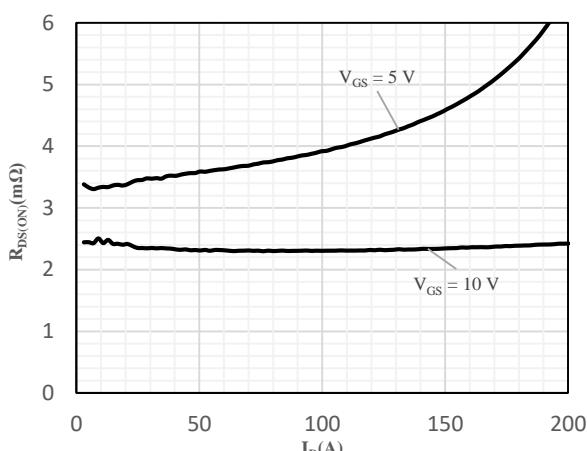
Notes:

1. Surface mounted on 1 inch<sup>2</sup> FR-4 board with 2OZ copper
2. The  $E_{AS}$  test condition is  $V_{DD} = 20V, L = 0.1\text{mH}, V_{GS} = 10V$ , Starting  $T_J = 25^\circ\text{C}$
3. Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$

### Ratings and Characteristics Curves (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

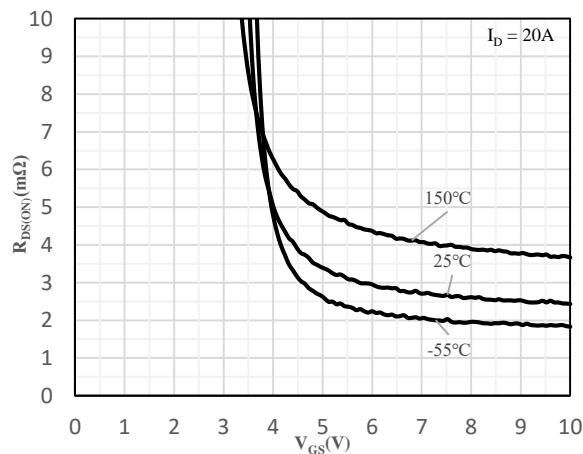


**Fig 1** Typical Output Characteristics

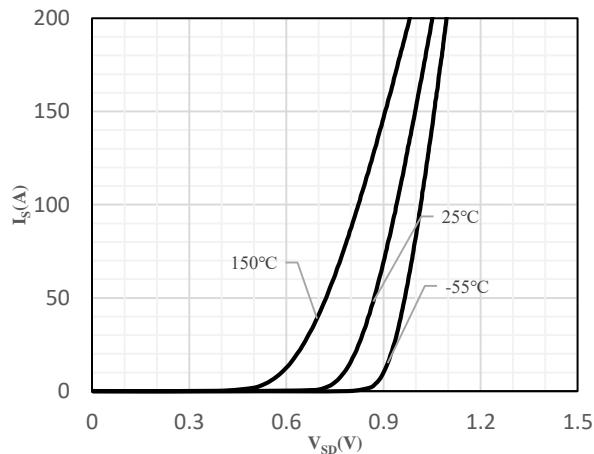


**Fig 2** On-Resistance vs. Drain Current

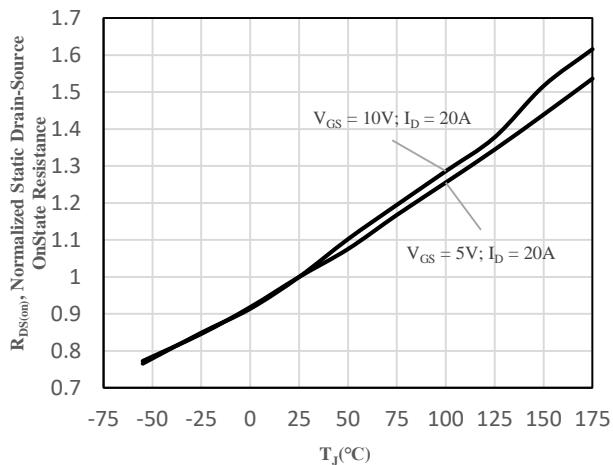
and Gate Voltage



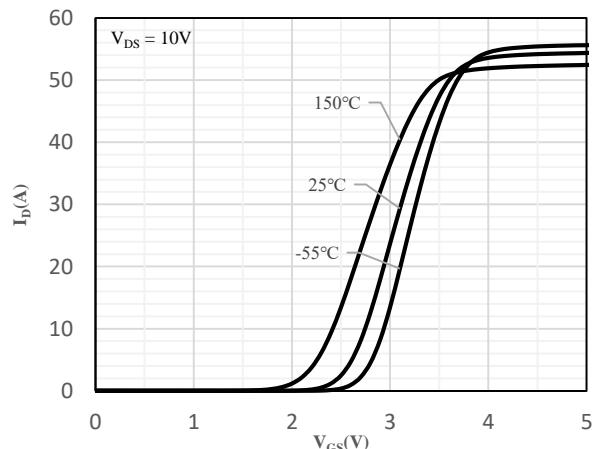
**Fig 3** On-Resistance vs. Gate-Source Voltage



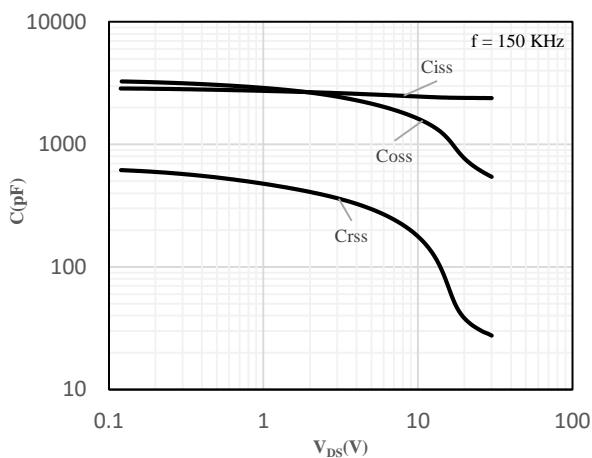
**Fig 4** Body-Diode Characteristics



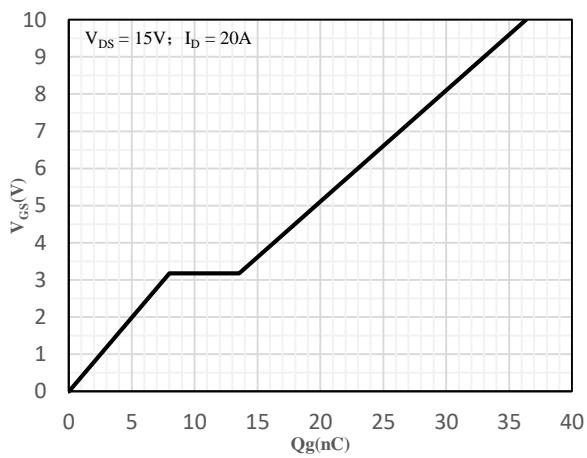
**Fig 5** Normalized On-Resistance vs. Junction  
Temperature



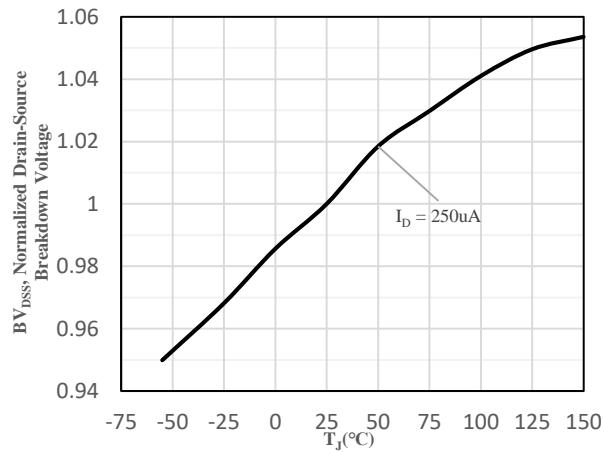
**Fig 6** Transfer Characteristics



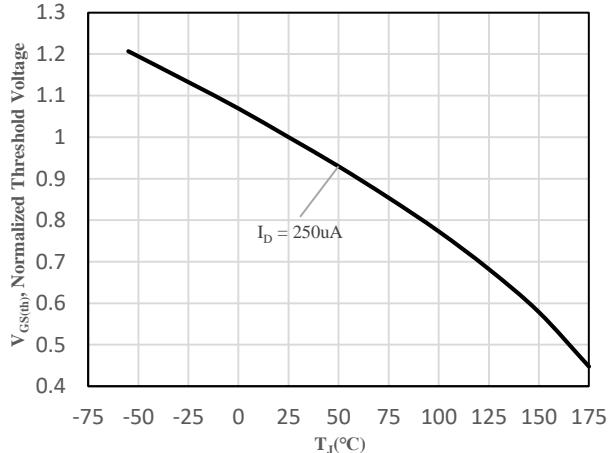
**Fig 7 Capacitance Characteristics**



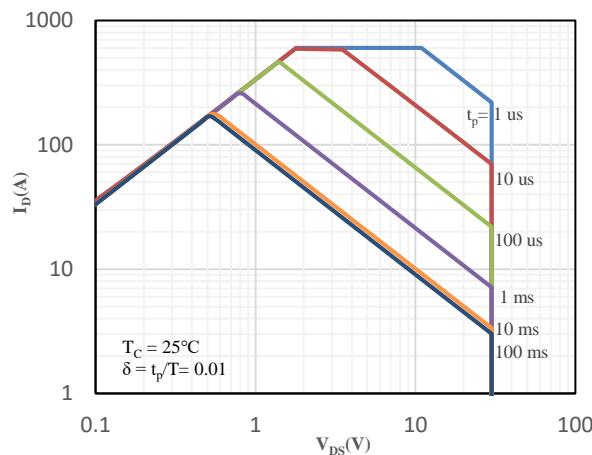
**Fig 8 Gate-Charge Characteristics**



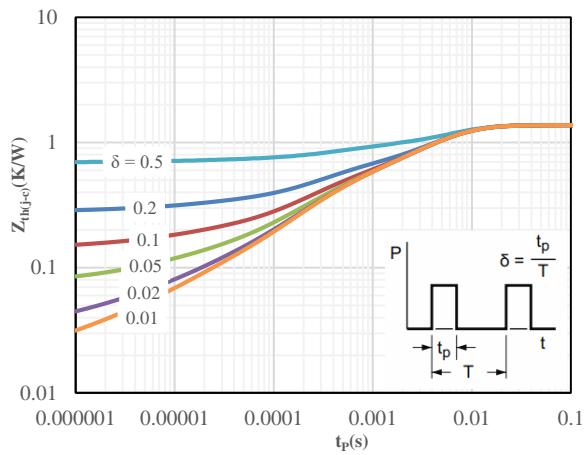
**Fig 9 Normalized Breakdown Voltage  
vs. Junction Temperature**



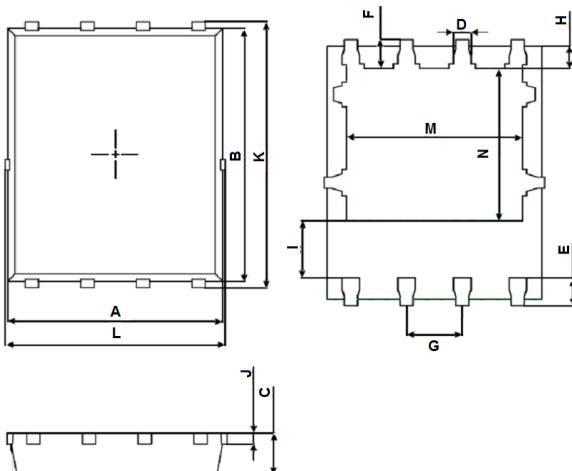
**Fig 10 Normalized V<sub>GS(th)</sub> vs. Junction Temperature**



**Fig 11 Safe Operation Area**

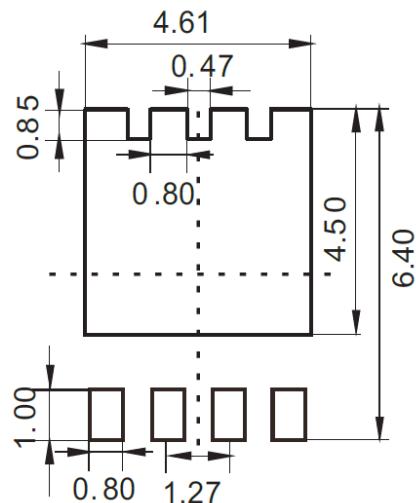


**Fig 12 Maximum transient thermal impedance**

**Package Outline Dimensions** (Unit: mm)


PDFN5x6-8L		
Dimension	Min.	Max.
A	4.824	4.976
B	5.674	5.826
C	0.900	1.000
D	0.350	0.450
E	0.559	0.711
F	0.574	0.726
G	1.250	1.290
H	0.424	0.576
I	1.190	1.390
J	0.154	0.354
K	5.974	6.126
L	4.944	5.096
M	3.910	4.110
N	3.375	3.575

**Mounting Pad Layout** (Unit: mm)

**PDFN5x6-8L**

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